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# TOO **HOT** TO TEST

Thermal Management  
of ICs During Testing

F E B R U A R Y 9 - 11 , 2 0 2 1 **O N L I N E**

## Too Hot To Test

February 9 - 11, 2021

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accelerating thermal thinking



## MEPTEC - Too Hot To Test

Active Temperature Control at High Power Testing

Feb-11th, 2021





**Markus Kindler**  
Managing Director – ATT Systems GmbH



# Too Hot To Test?

Testing conditions are changing to the extreme

Full w

C

AI dev

Its

Active Temperature Control is Crucial –  
Thermal Chuck is an Integral Part of the Test Cell

No pro

Advan

Low T

Some solutions exist – some challenges remain



Systems



# What is a Thermal Chuck System?

## Air Cooled



-40C to +200C

-60C to +200C

## Modular Base Chuck System



Universal chuck and controller

2 independent cooling circuits

+20C to +200C without chiller

## Liquid Cooled



-20C to +200C

-40C to +200C

-60C to +200C



# Today's Requirements

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Power dissipation: 300 Watts to 2000 Watts

Voltage

Electr

Temp

Flatne

**Multi-Dimensional Requirements:**

@Wide Temperature Range  
@Uniformity

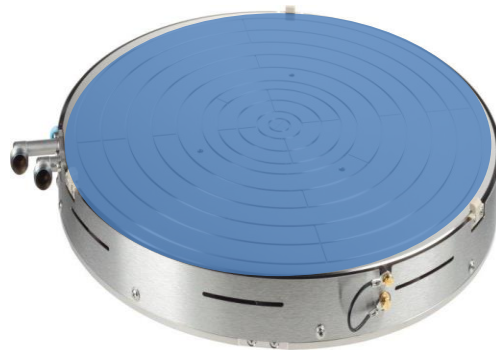
High Rigidity for 550 kgf load, thin wafer (50 $\mu$ m), warped substrates





# 3 Application Examples

Full Wafer Contact  
DRAM, Flash, HBM



Contact Area: Large  
Parallelism: High

Power/Die: Low  
Density: Low (3W/cm<sup>2</sup>)

Heat transfer: up to 2000W  
Temp. Range: -40°C to +125°C

100x100mm  
E.g. Microcontroller



Contact Area: Medium  
Parallelism: Medium/Low

Power/Die: Medium/High  
Density: Medium (10W/cm<sup>2</sup>)

Heat transfer: up to 1000W  
Temp. Range: -40°C to +125°C

20x20mm  
E.g. 5G or GPU devices



Contact Area: Small  
Parallelism: Low

Power/Die: High  
Power Density: High (125W/cm<sup>2</sup>)

Heat transfer: up to 500W  
Temp. Range: -40°C to +125°C

Roadmaps to wider temperature ranges and higher testing power!



# Power Dissipation

## Air-Cooled or Liquid-Cooled?

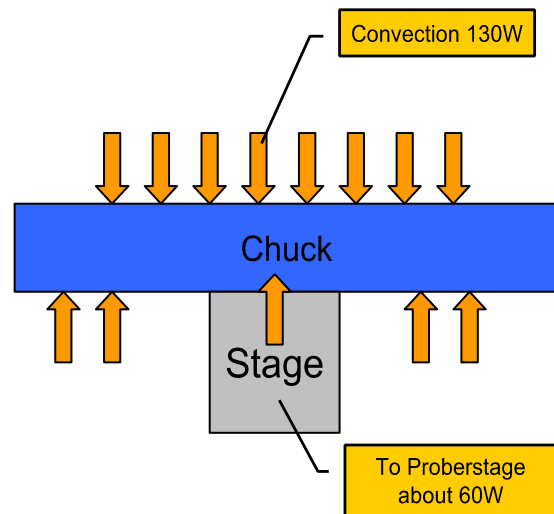
...a little bit of theory...





# Thermal Load – Idle Mode (Convection)

Chuck Temperature:  $-40^{\circ}\text{C}$   
Thermal Load at “idle” mode



Thermal Load through convection:

The thermal load depends on:

- Temperature difference
- Surface area
- Heat transfer coefficient

$$\dot{Q} = \Delta T \alpha A$$

$$\Delta T = 65\text{K}$$

$$\alpha \approx 13\text{W} / \text{m}^2\text{K}$$

$$A = 0,155\text{m}^2$$

$$\dot{Q} \approx 130\text{W}$$

Additional power of around 50W transferred through prober-stage

Idle Thermal Load is around 180W



# Thermal Load – During Testing

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Chuck Temperature: -40°C

Thermal Load through Probecard:

Therm

## At -40°C Chuck Temperature:

Thermal Load “Idle”: 180W

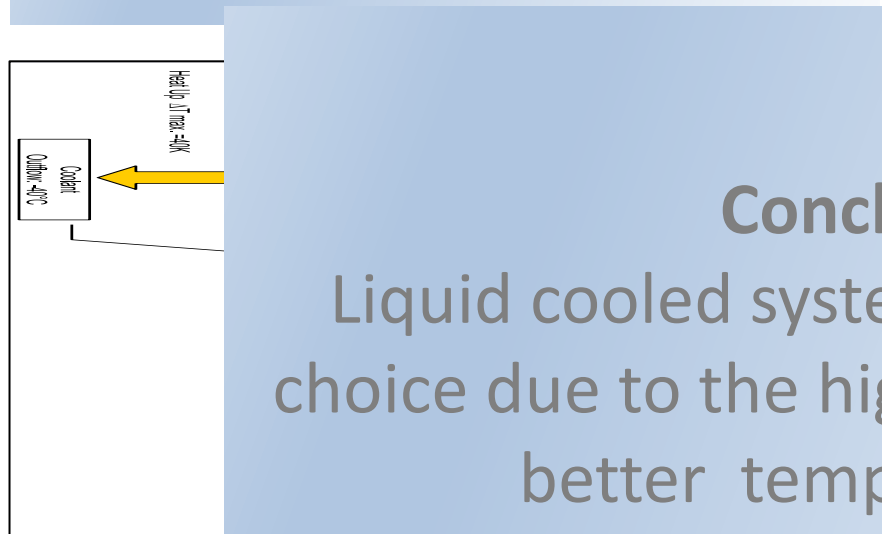
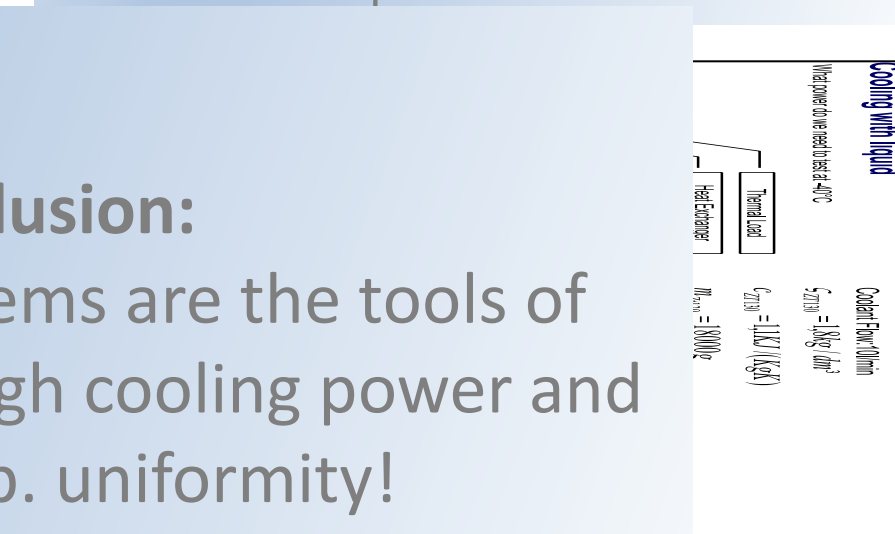
Thermal Load “Testing”: 50W to 2KW

Total Thermal Load: 230W to 2.2KW

Thermal Load during testing is >1100 Watts



# Air-Cooled or Liquid-Cooled?

Air-Cooled	Liquid-Cooled
	
Max. Cooling Power	10W
Effective Cooling	High
$\Delta T$ high – impact on temp. uniformity	Reasonable cooling fluid consumption
High air-flow@high pressure	Wider temp range might require other fluids

**Conclusion:**  
Liquid cooled systems are the tools of choice due to the high cooling power and better temp. uniformity!



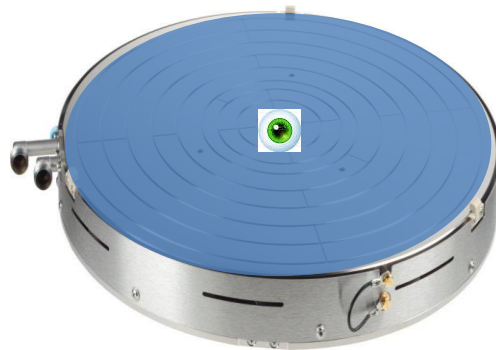


**Why MultiSense?**  
**You can't control what you can't see!**

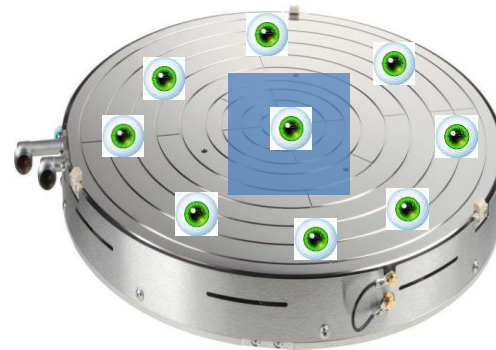


# Temperature Detection - MultiSense

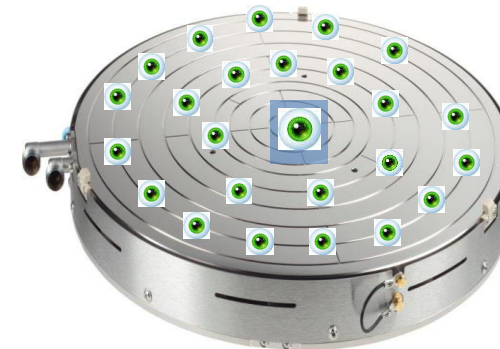
Full Wafer Contact  
Up to 2000 Watts



100x100mm  
Up to 1000 Watts



20x20mm  
Up to 700 Watts



For Full Wafer Contact applications one control sensor is enough  
Smaller contact areas require multiple control sensors to detect temp changes  
Number of in-built sensors is limited due to chuck complexity  
Number of AddOn sensors is scalable, currently up to 25 sensors  
Requires advanced temp control algorithms



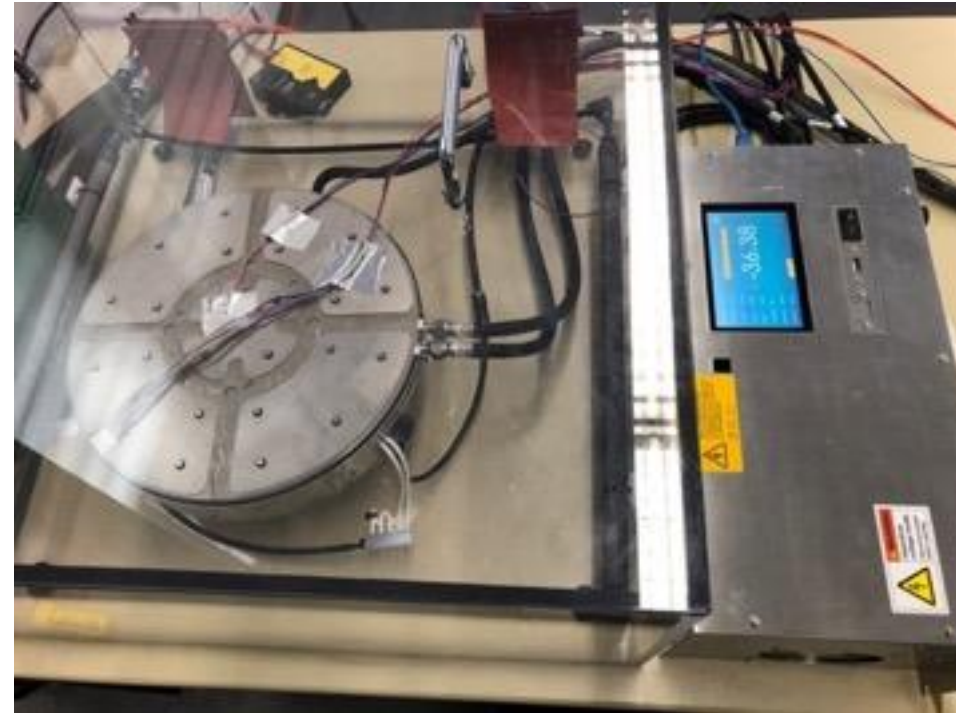
# Full Wafer Contactor

ATT Sealed Test Box

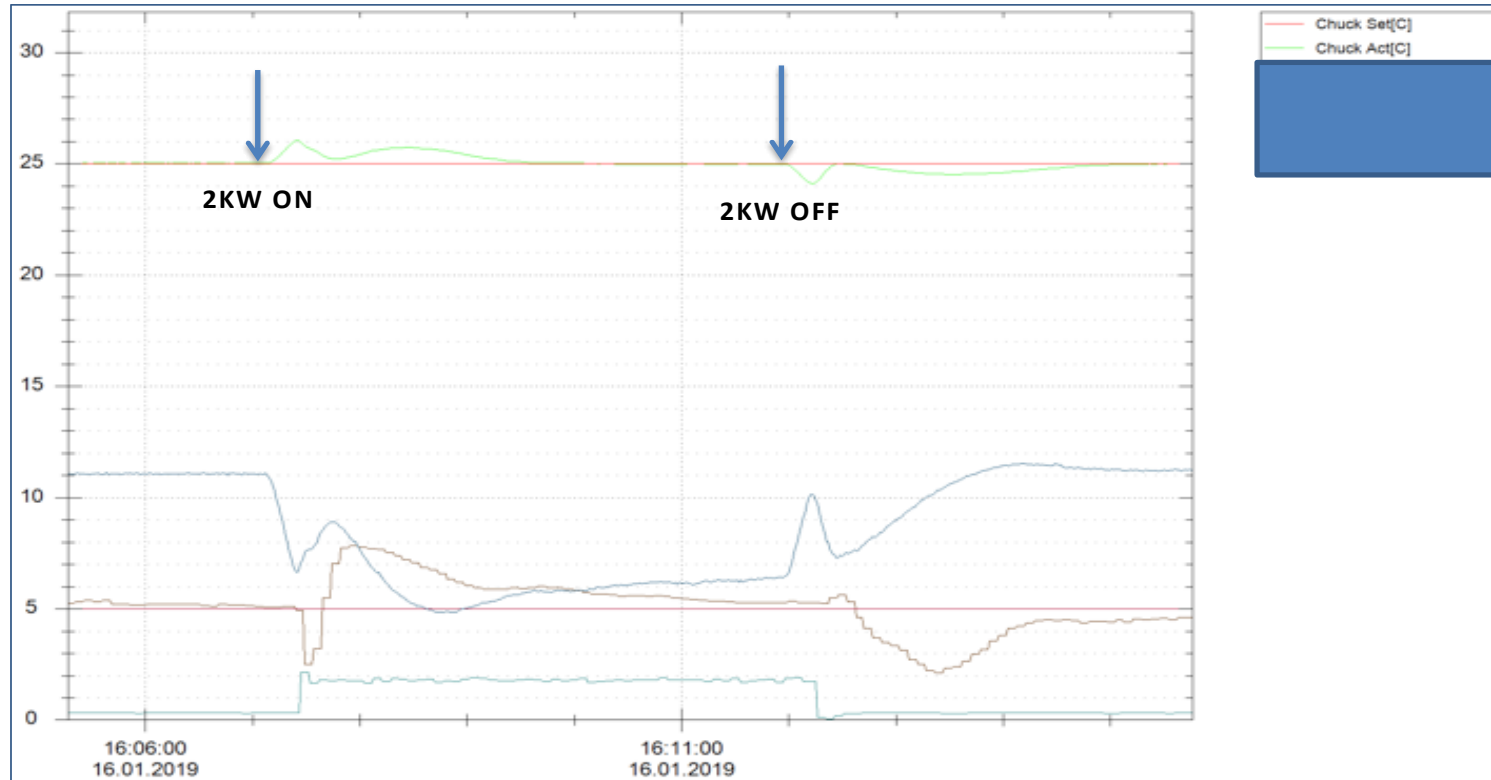
Chuck – L300T-EX LTR HP

Chiller – L80J (liquid cooled)

Power Plate (up to 2000W)



# Full Wafer Contactor +25C 2KW

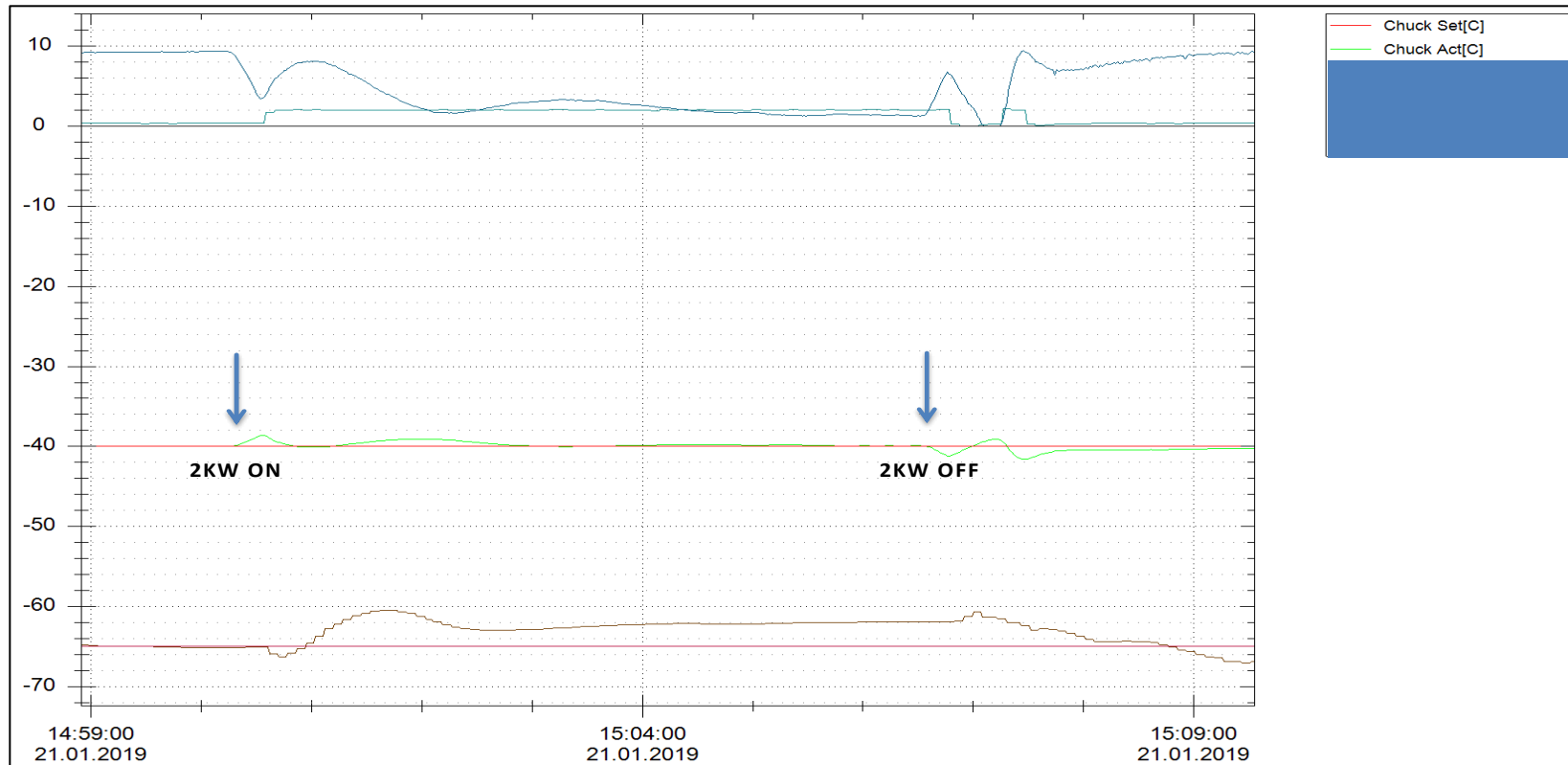


Able to dissipate 2KW – Temperature control within 1K





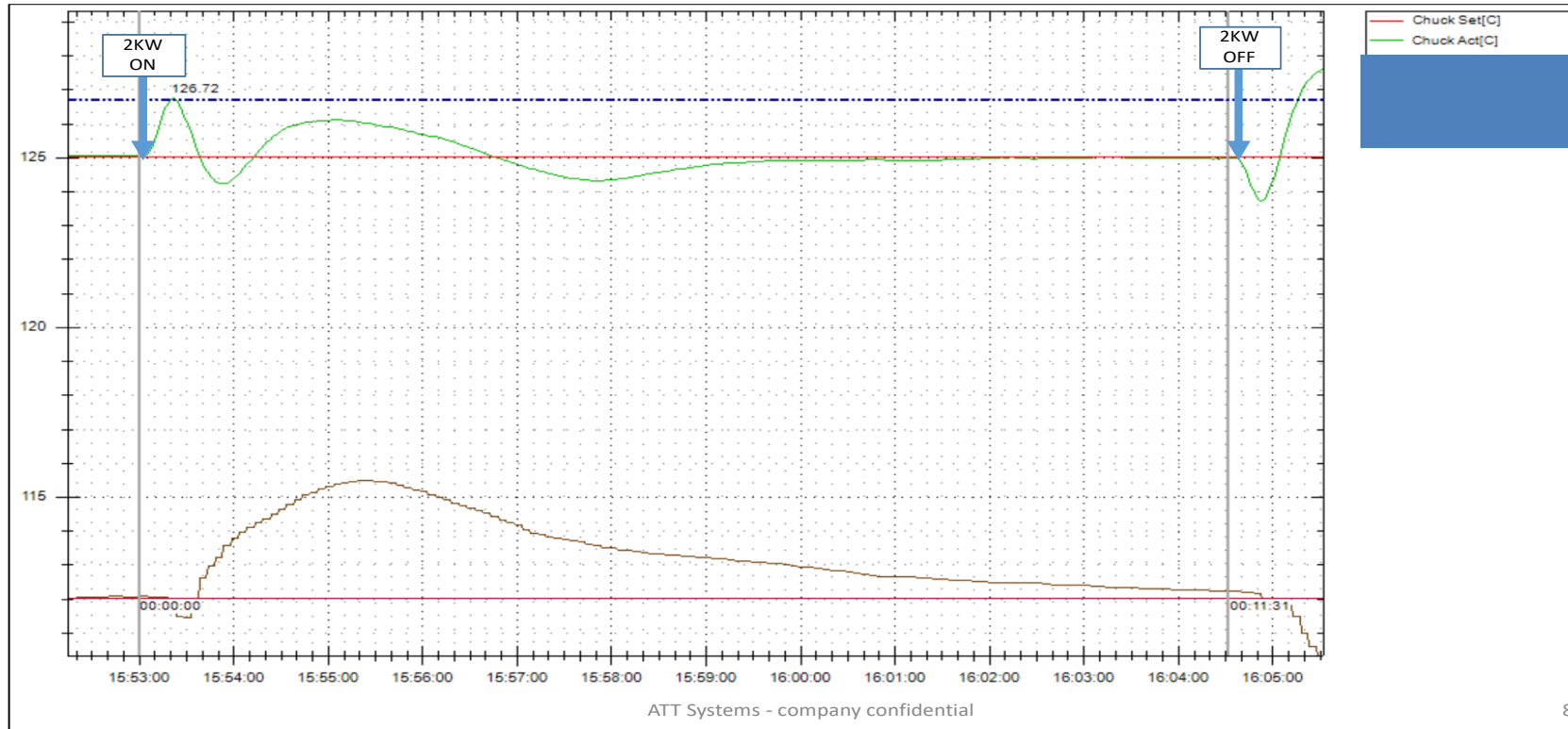
# Full Wafer Contactor -40C 2KW



Able to dissipate 2KW – Temperature control within 2K



# Full Wafer Contactor +125C 2KW



Able to dissipate 2KW – Temperature control within 2K



# 100x100mm

ATT Sealed Test Box

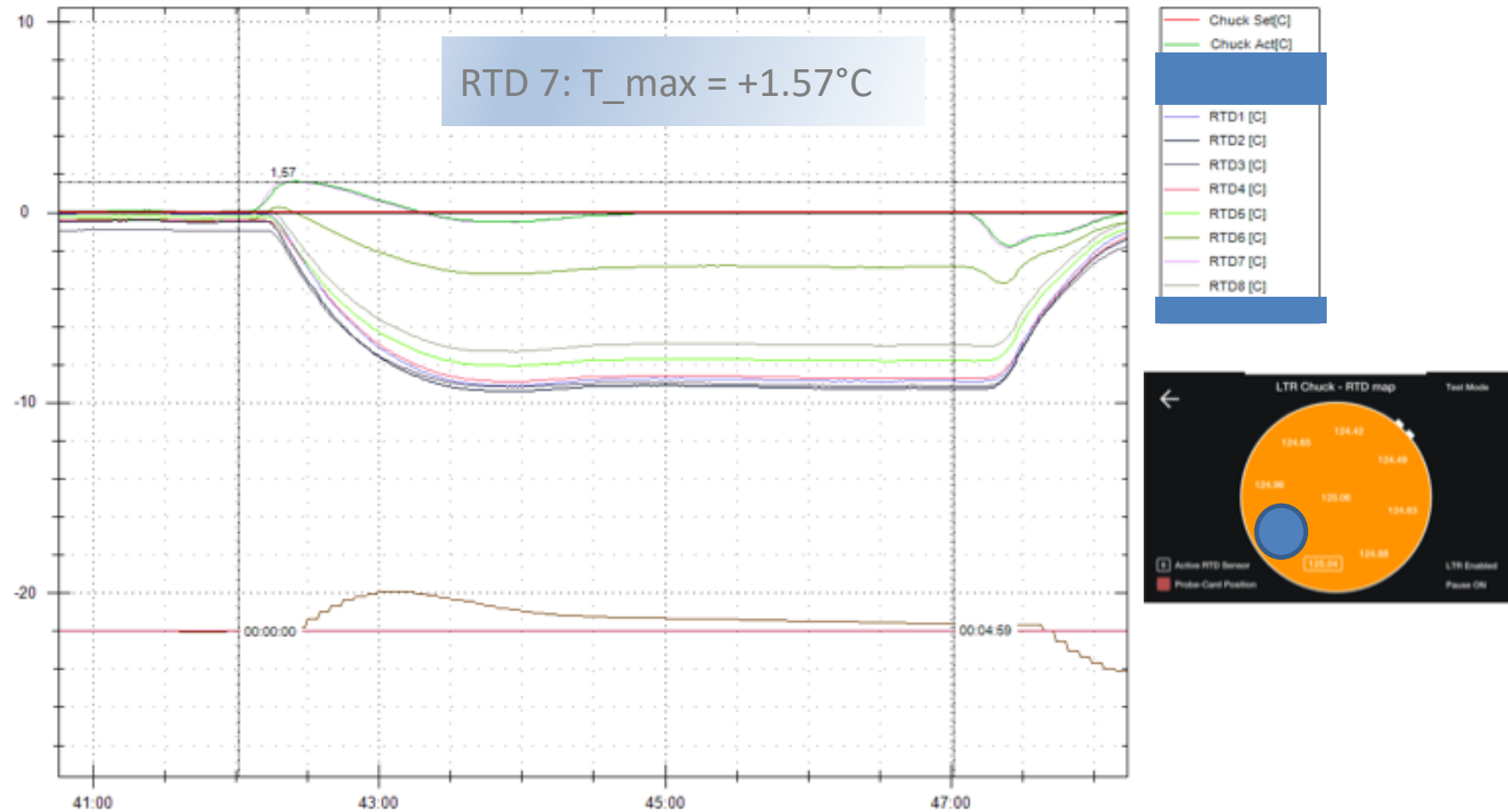
Chuck – L300T-EX LTR – 9 Sensors

Chiller – L60J (liquid cooled)

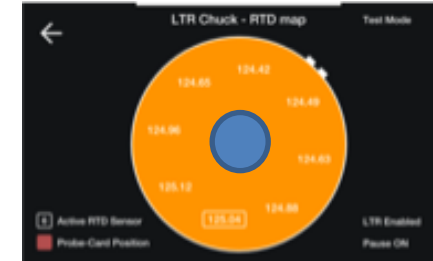
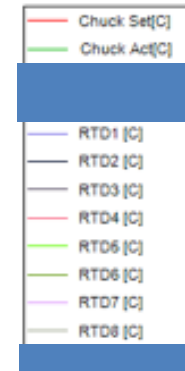
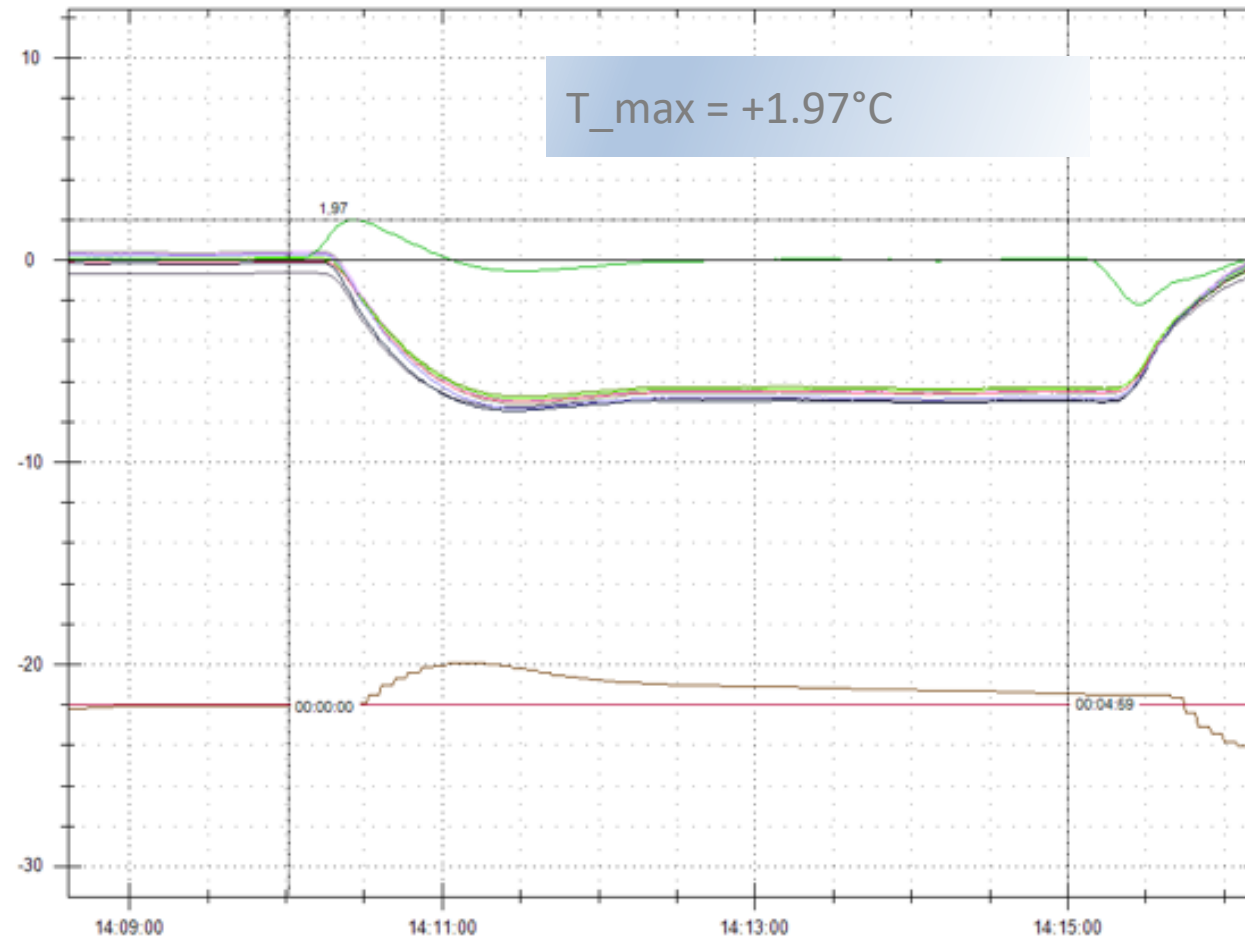
Power Plate (100x100mm)



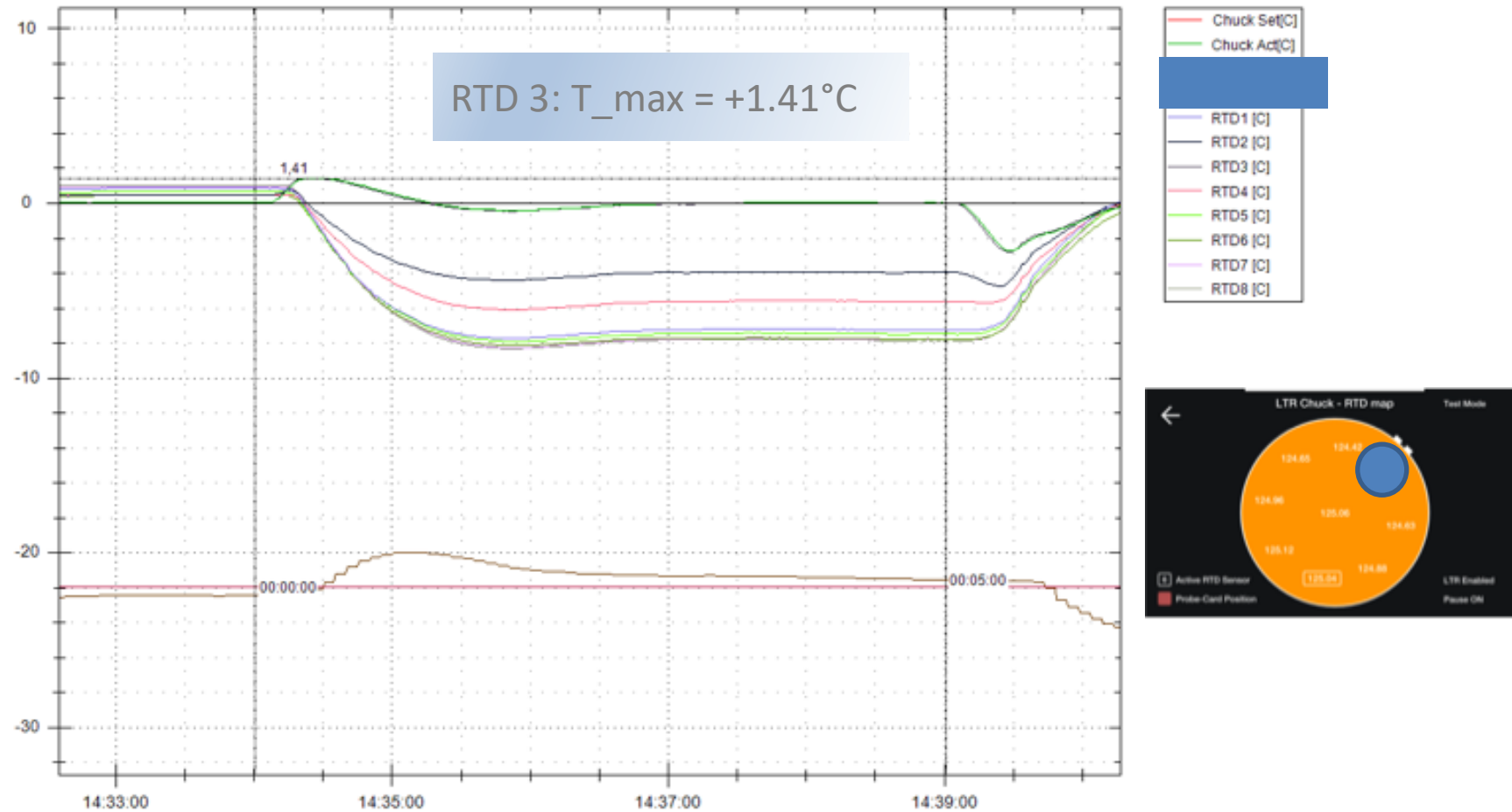
## 0C – Top Position 400W



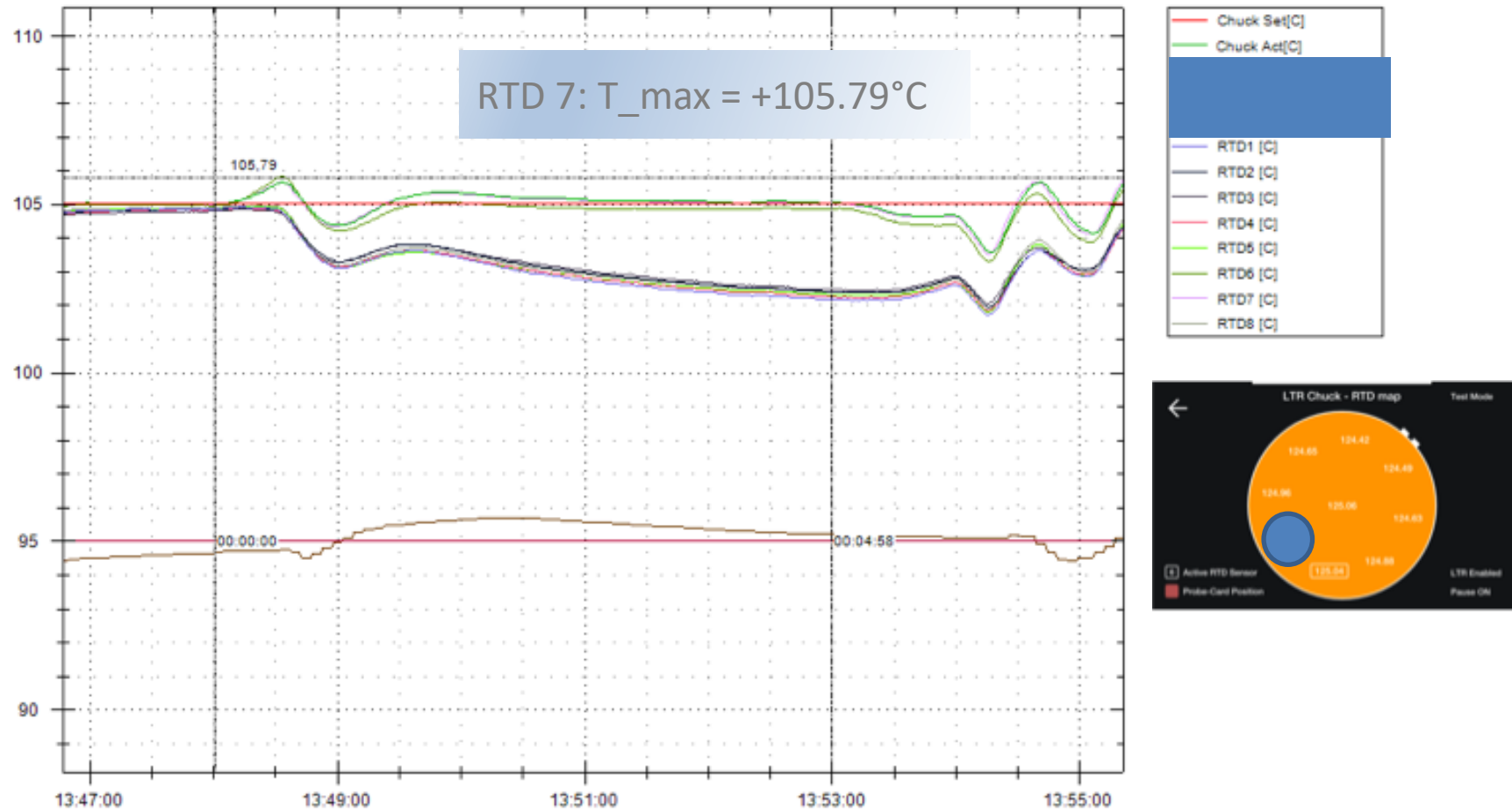
# 0C – Center Position 400W



## 0C – Tube Position 400W

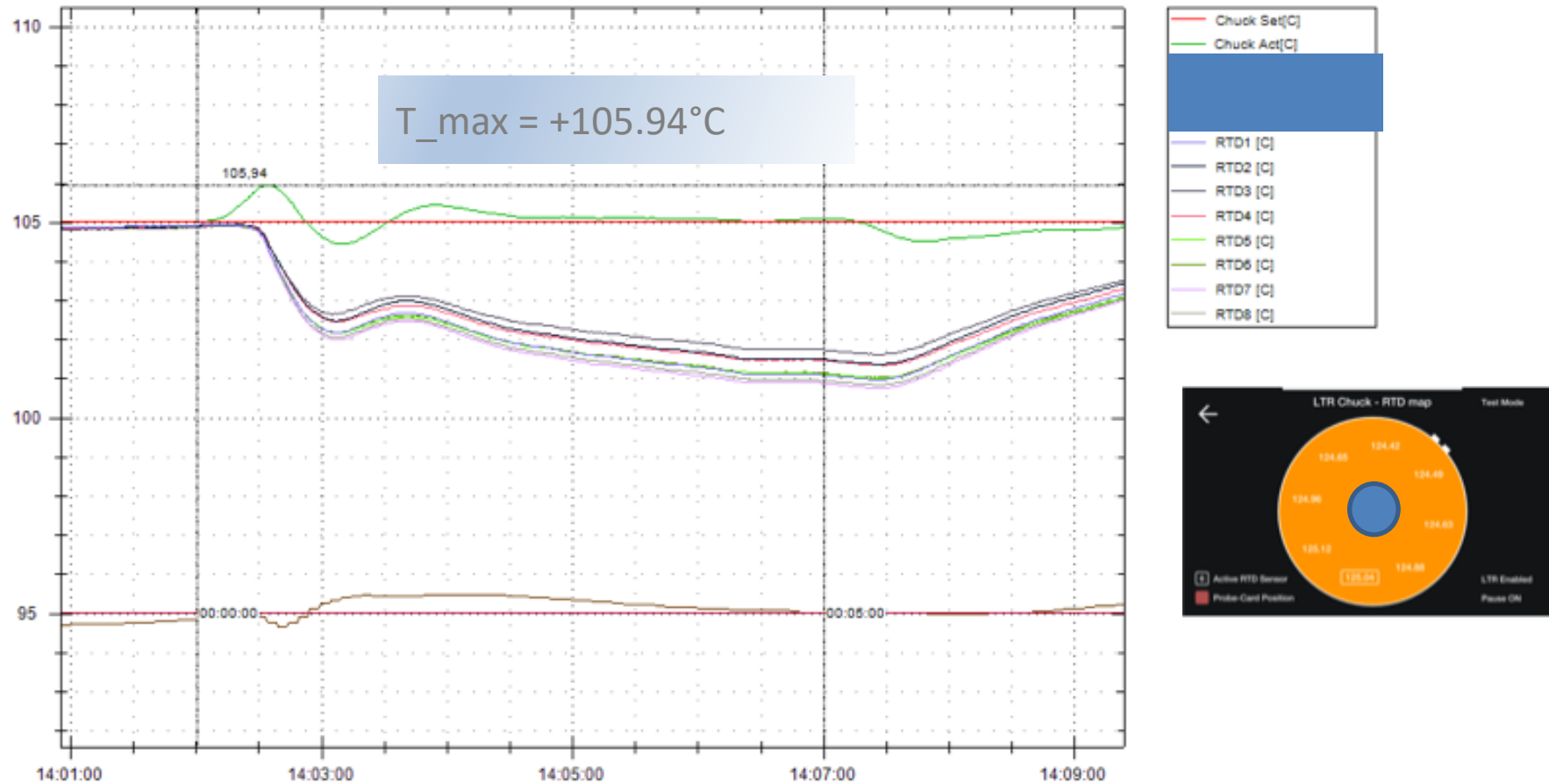


## +105C – Top Position 400W

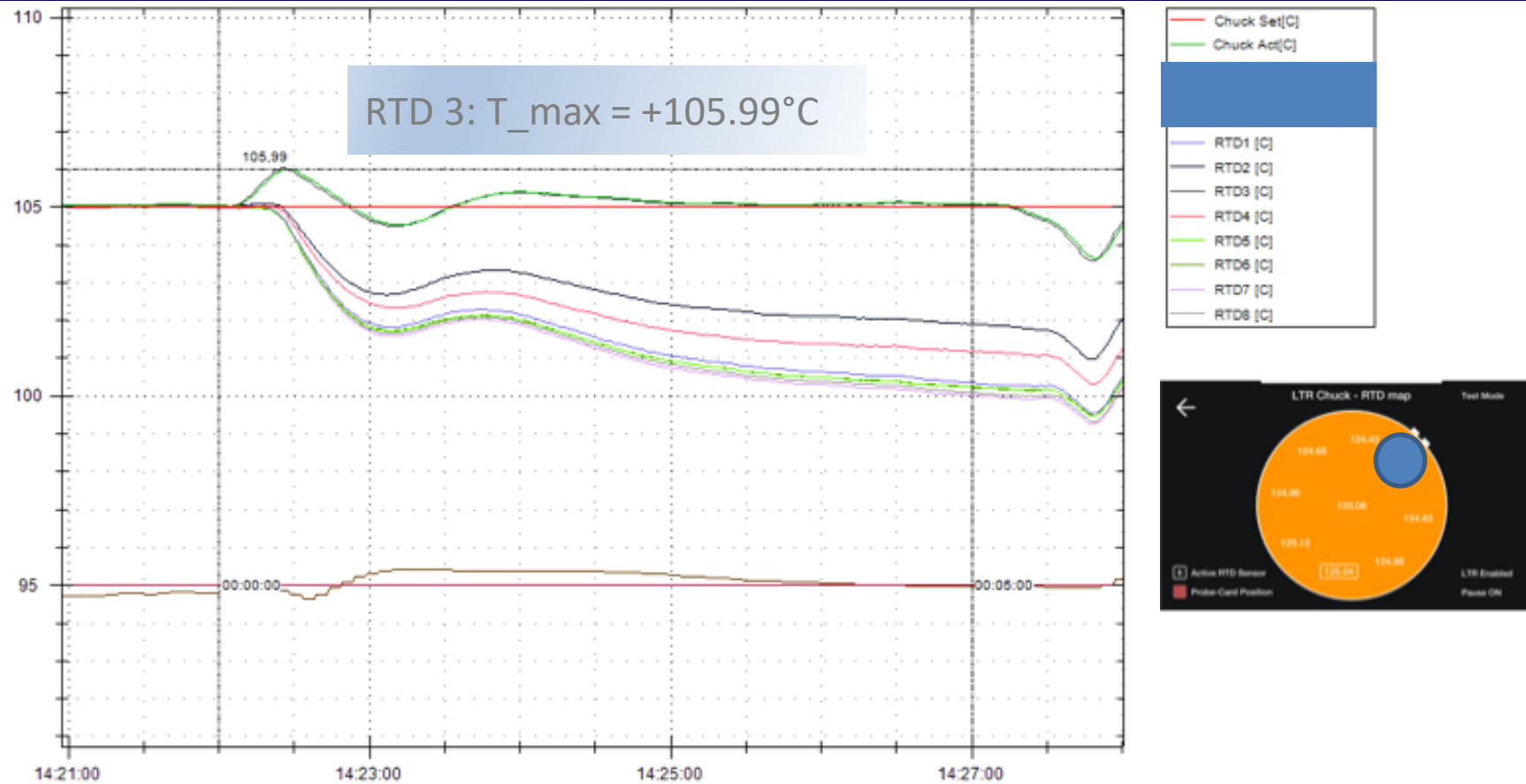




# +105C – Center Position 400W



## +105C – Tube Position 400W



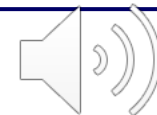
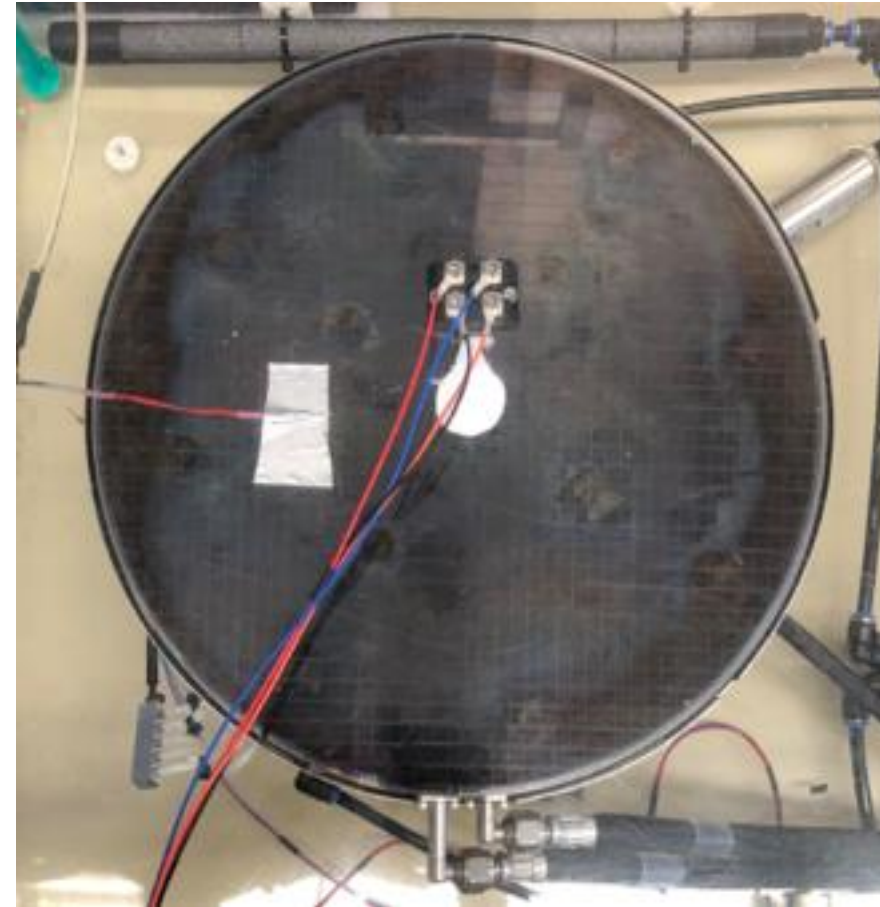
## 23x23mm Contact Area - Test Set Up

ATT Sealed Test Box

Chuck – L300T-EX LTR – 9 Sensors

Chiller – L60J (liquid cooled)

Heater Plate 23x23mm (200W max)



# Test Conditions

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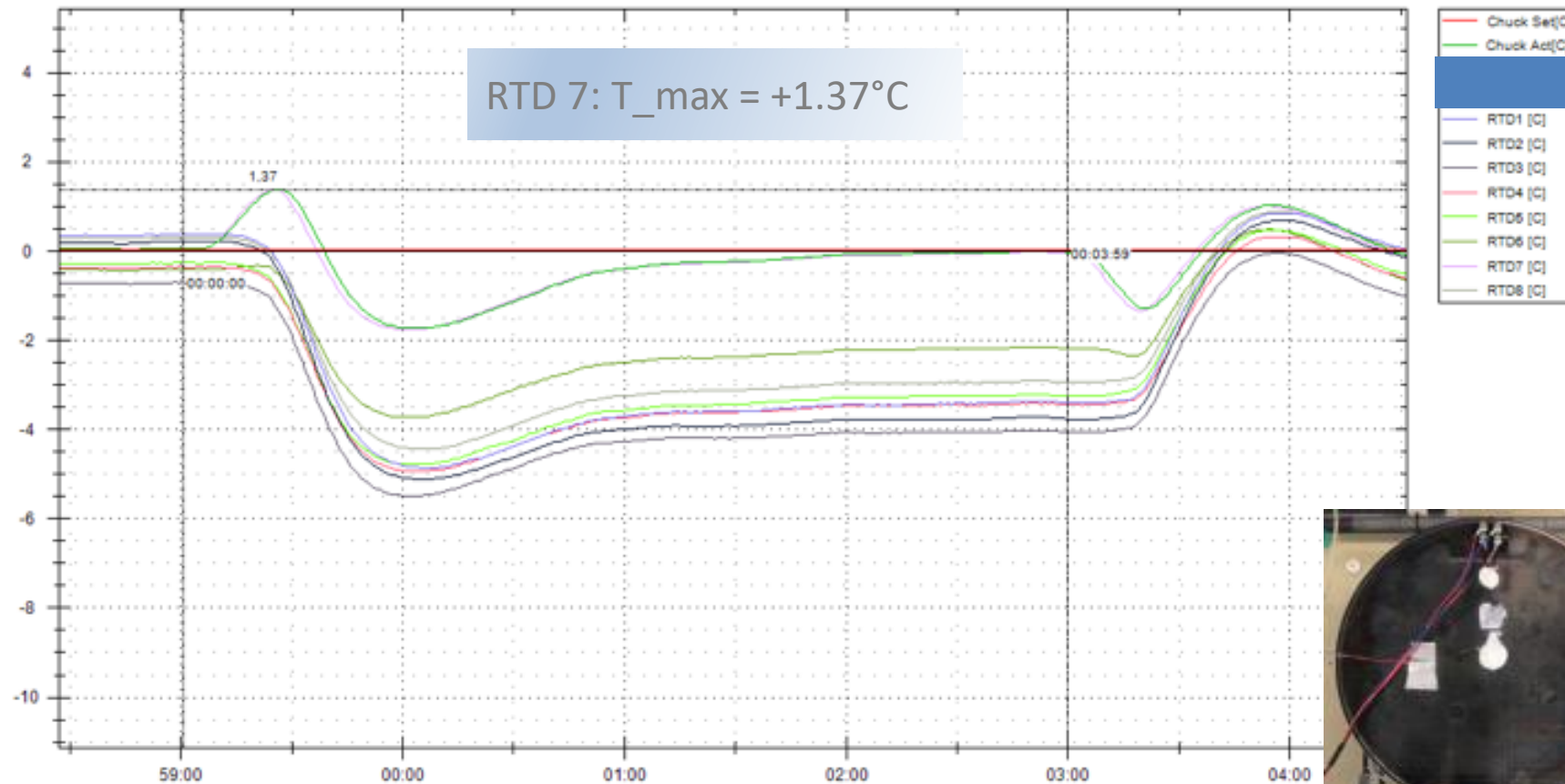
Advanced Control Parameter

0°C: 100W - +105°C: 160W

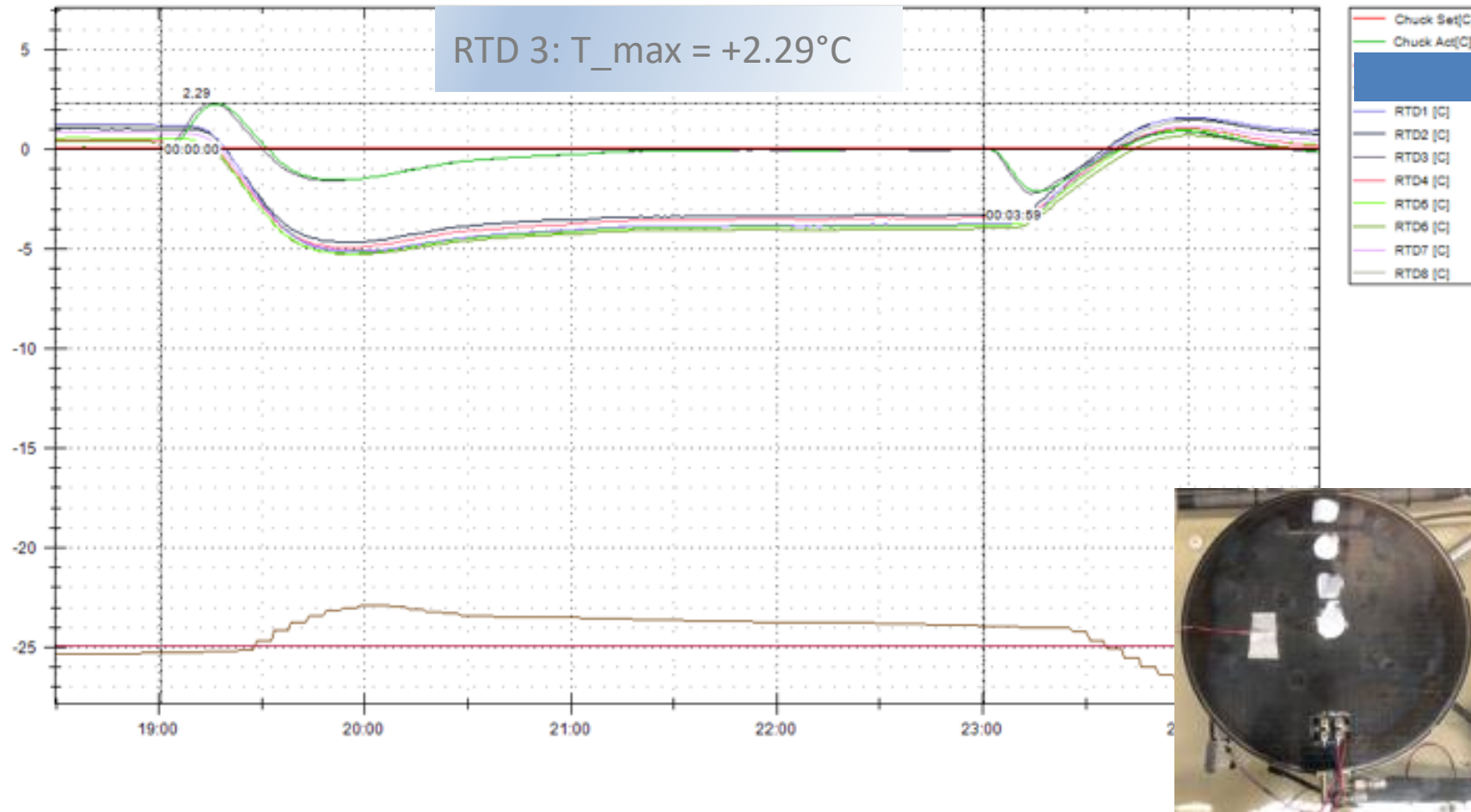
Test Time: 4 minutes at 0°C, 15 seconds at +105°C



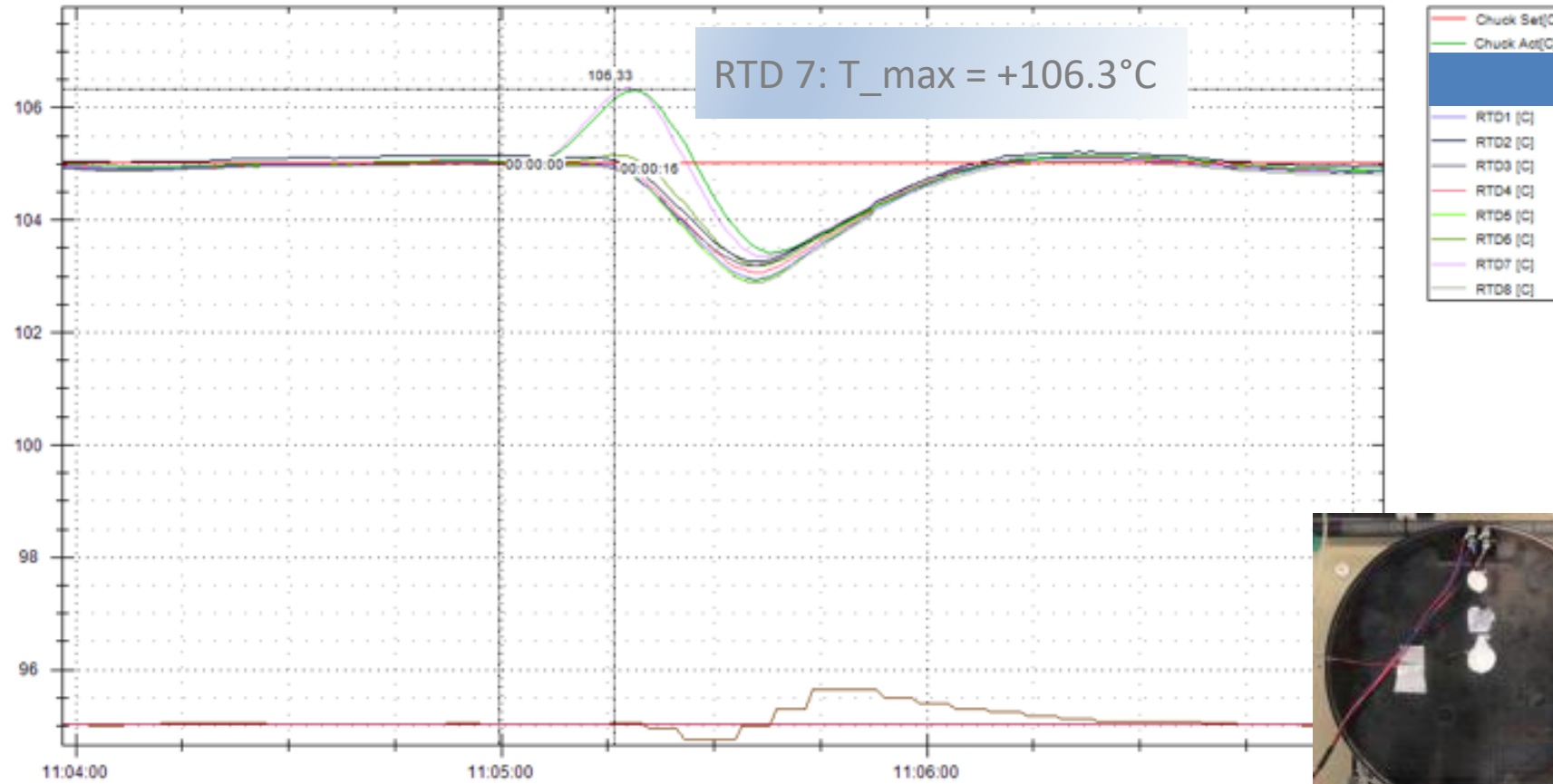
# 0C – Top Position 100W



# 0C – Tube Position 100W

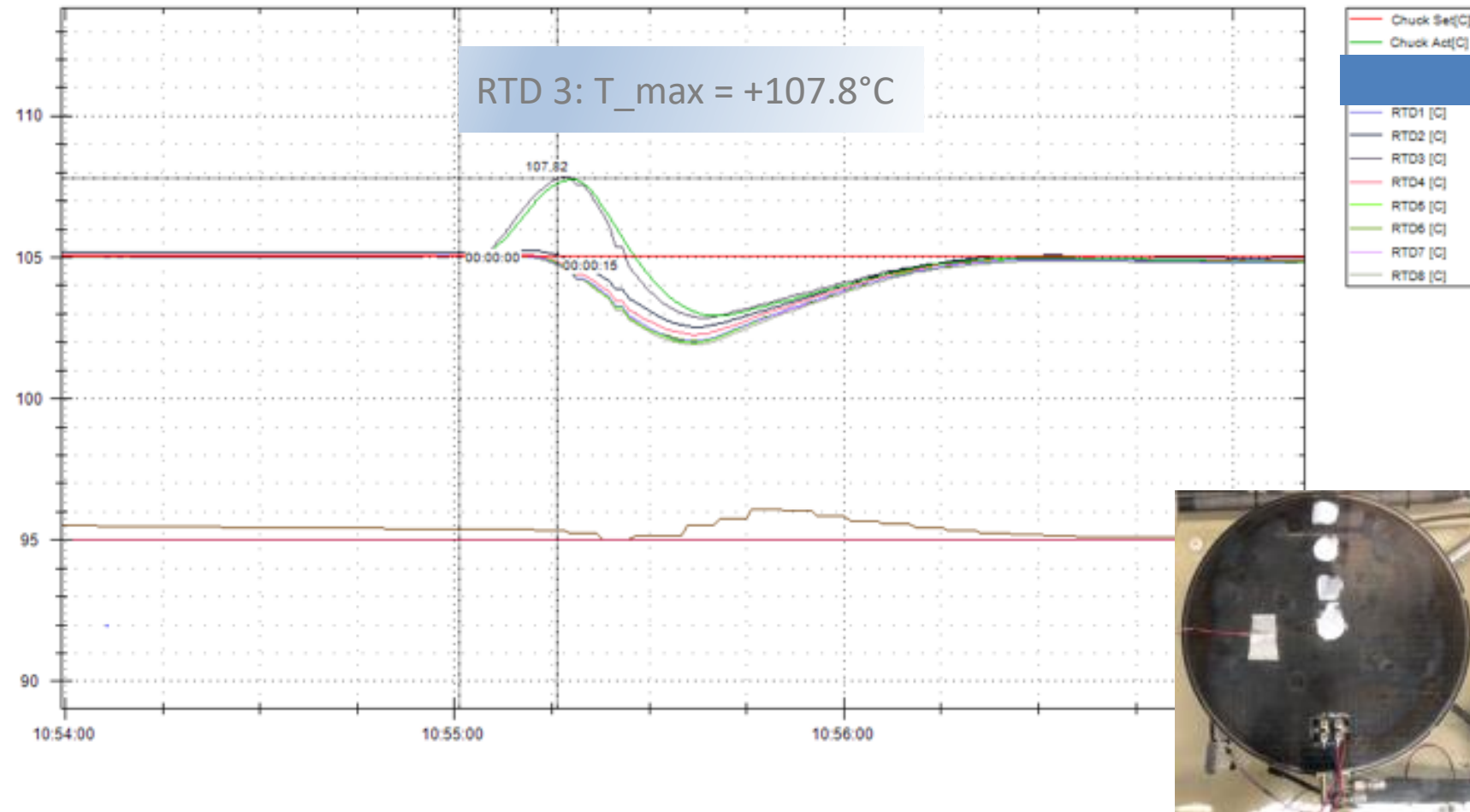


# +105C – Top Position 160W





# +105C – Tube Position 160W



# Summary

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High Power Dissipation requires Liquid Cooled Systems

Full Wafer Contact up to 2KW – doable

100x100mm up to 400W – doable (higher power possible with L80J)

23x23mm up to 160W – doable (higher power possible with L80J)

23x23mm Next tests will be done with a 21 or 25 sensor chuck

-40°C to +125°C covered with single fluid

Wider temp range requires new fluids (high BP and low viscosity) or

Dedicated prober for certain temperature ranges



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# Thank You!

## Q&A

Contact:

ATT Systems GmbH

Tel.: +49.89.89.94.82.0

Fax: +49.89.89.94.82.28

Mail: [info@att-systems.com](mailto:info@att-systems.com)



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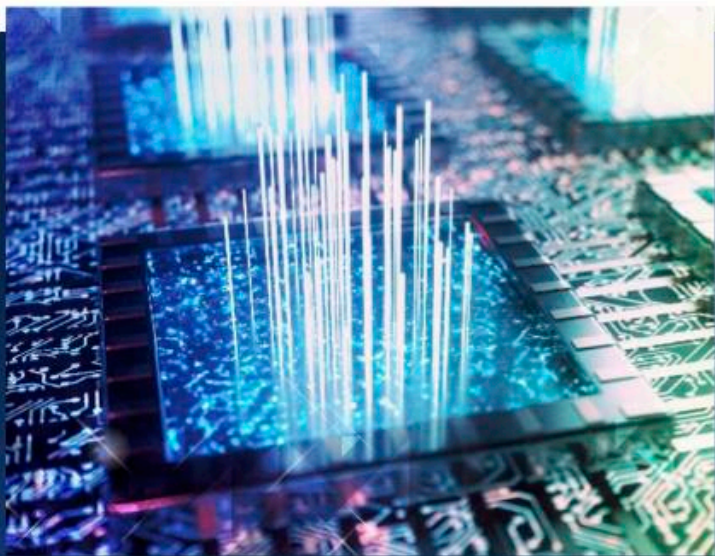
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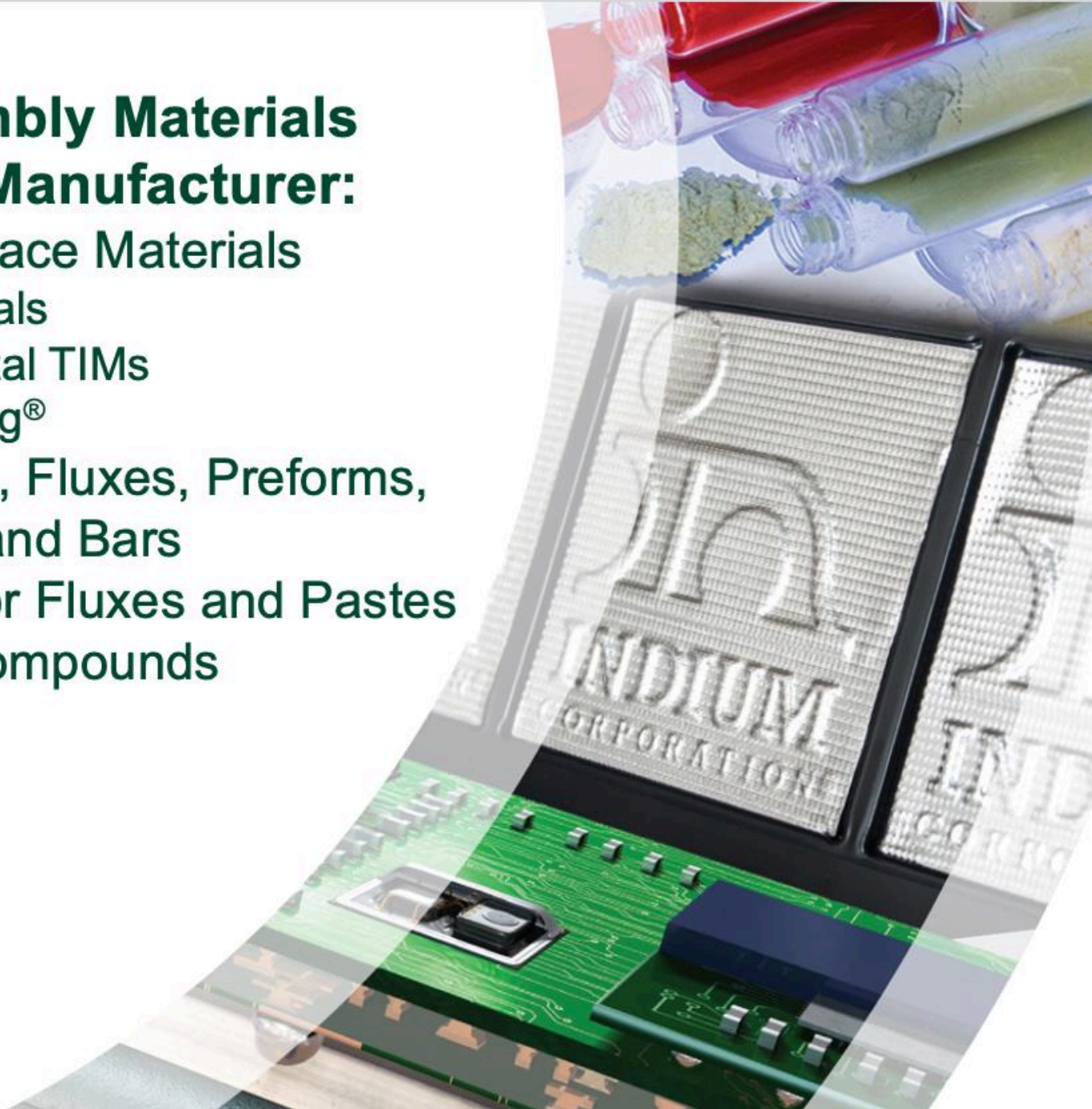
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